

X-RAY ANALYTICAL MICROSCOPE (XRF)



Make : Horiba, Japan

Model : XGT-5200 X-ray analytical microscope

Source : X-ray tube 50 kV max, 1 mA, with Rh target

Detector : Peltier cooled Silicon Drift Detector (SDD)

Elements Detected: Na to U (with sample at normal atmospheric pressure)

CCD camera : Magnification 30 and 100 approx.

Samples : Metal plates, powders and coatings

Energy Range: 0 - 40 keV

Maximum Measurement Area / Maximum Sample Size:

100 mm x 100 mm / 350 mm x 400 mm x 40 mm

Description :

The XGT-5200 X-ray Fluorescence micro-analyzers combine the fast, non-destructive elemental analysis of energy dispersive X-ray Fluorescence (EDXRF) with the capability to pinpoint individual particles with diameters down to 10 μm in size. Automated sample scanning provides detailed images of element distribution, over areas as large as 10cm x 10cm.